

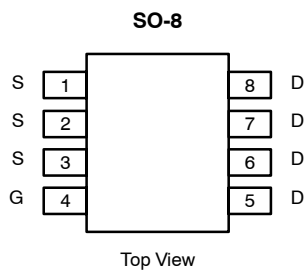


P-Channel 30-V (D-S) MOSFET

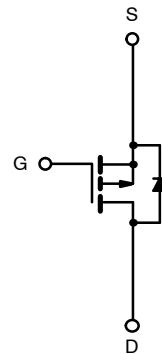
PRODUCT SUMMARY		
V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (A)
-30	0.042 @ $V_{GS} = -10$ V	-5.7
	0.055 @ $V_{GS} = -6$ V	-5.0
	0.070 @ $V_{GS} = -4.5$ V	-4.4

FEATURES

- TrenchFET® Power MOSFET



Ordering Information: Si9435BDY
Si9435BDY-T1 (with Tape and Reel)



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)					
Parameter	Symbol	10 secs	Steady State	Unit	
Drain-Source Voltage	V_{DS}	-30		V	
Gate-Source Voltage	V_{GS}	± 20			
Continuous Drain Current ($T_J = 150^\circ\text{C}$) ^a	I_D	$T_A = 25^\circ\text{C}$	-5.7	-4.1	A
		$T_A = 70^\circ\text{C}$	-4.6	-3.2	
Pulsed Drain Current	I_{DM}	-30			
continuous Source Current (Diode Conduction) ^a	I_S	-2.3	-1.1		
Maximum Power Dissipation ^a	P_D	$T_A = 25^\circ\text{C}$	2.5	1.3	W
		$T_A = 70^\circ\text{C}$	1.6	0.8	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 150		$^\circ\text{C}$	

THERMAL RESISTANCE RATINGS					
Parameter	Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^a	R_{thJA}	$t \leq 10$ sec	40	50	$^\circ\text{C/W}$
		Steady State	70	95	
Maximum Junction-to-Foot (Drain)	R_{thJF}	24	30		

Notes

a. Surface Mounted on 1" x 1" FR4 Board.

SPECIFICATIONS (T _J = 25 °C UNLESS OTHERWISE NOTED)						
Parameter	Symbol	Test Condition	Min	Typ ^a	Max	Unit
Static						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250 μA	-1.0		-3.0	V
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ±20 V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -30 V, V _{GS} = 0 V			-1	μA
		V _{DS} = -30 V, V _{GS} = 0 V, T _J = 70 °C			-5	
On-State Drain Current ^b	I _{D(on)}	V _{DS} ≤ -10 V, V _{GS} = -10 V	-20			A
		V _{DS} ≤ -5 V, V _{GS} = -4.5 V	-5			
Drain-Source On-State Resistance ^b	r _{DS(on)}	V _{GS} = -10 V, I _D = -5.7 A		0.033	0.042	Ω
		V _{GS} = -6 V, I _D = -5 A		0.043	0.055	
		V _{GS} = -4.5 V, I _D = -4.4 A		0.056	0.070	
Forward Transconductance ^b	g _{fs}	V _{DS} = -15 V, I _D = -5.7 A		13		S
Diode Forward Voltage ^b	V _{SD}	I _S = -2.3 A, V _{GS} = 0 V		-0.8	-1.1	V
Dynamic^a						
Total Gate Charge	Q _g	V _{DS} = -15 V, V _{GS} = -10 V, I _D = -3.5 A		16	24	nC
Gate-Source Charge	Q _{gs}			2.3		
Gate-Drain Charge	Q _{gd}			4.5		
Gate Resistance	R _g			8.8		Ω
Turn-On Delay Time	t _{d(on)}	V _{DD} = -15 V, R _L = 15 Ω I _D ≅ -1 A, V _{GEN} = -10 V, R _G = 6 Ω		14	25	ns
Rise Time	t _r			14	25	
Turn-Off Delay Time	t _{d(off)}			42	70	
Fall Time	t _f			30	50	
Source-Drain Reverse Recovery Time	t _{rr}		I _F = -1.2 A, di/dt = 100 A/μs		30	

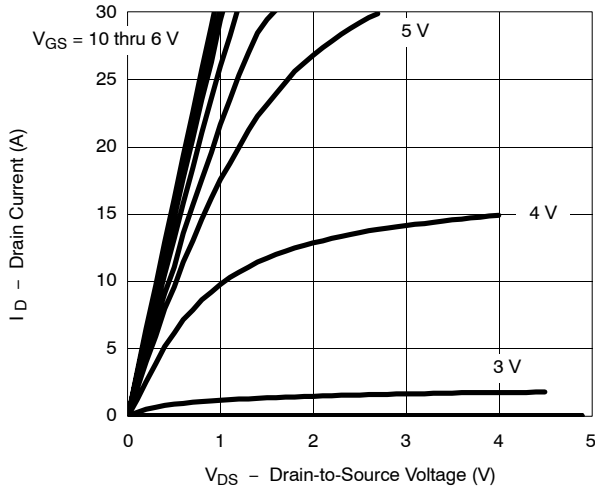
Notes

- a. Guaranteed by design, not subject to production testing.
b. Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2%.

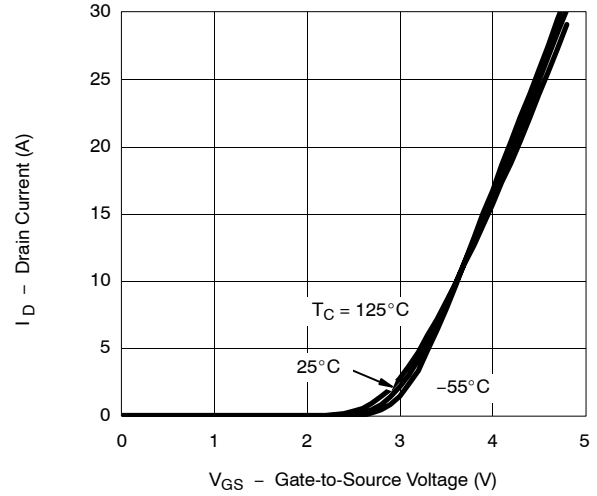


TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

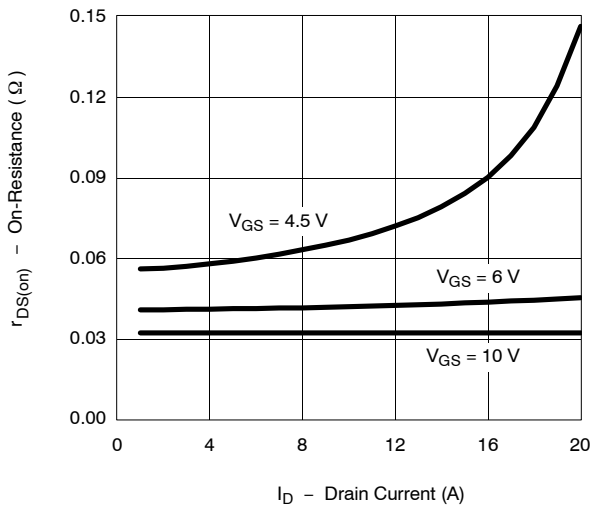
Output Characteristics



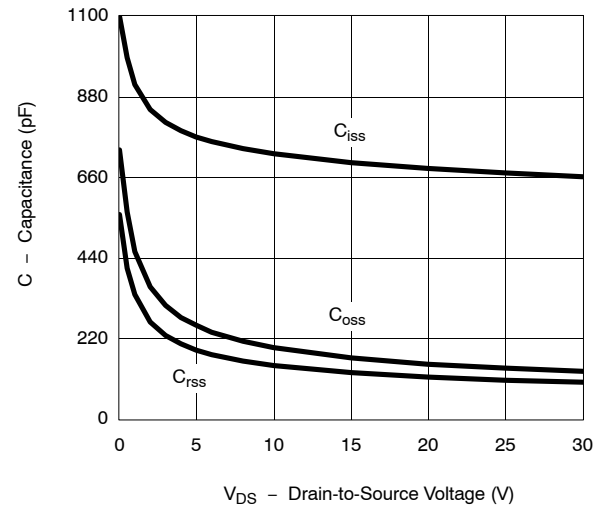
Transfer Characteristics



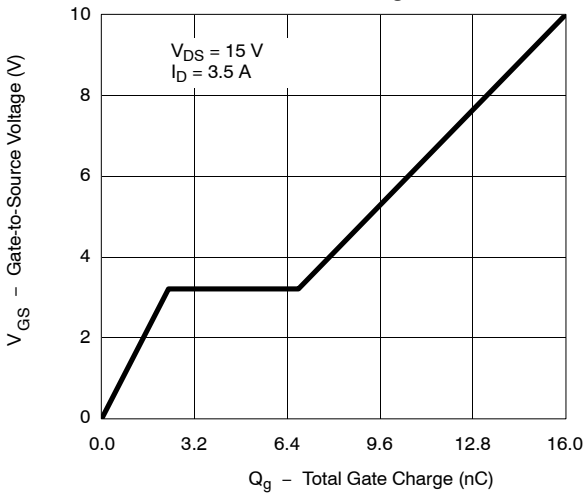
On-Resistance vs. Drain Current



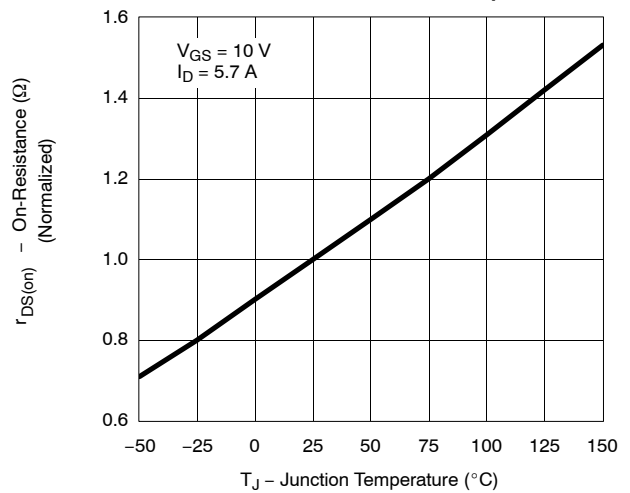
Capacitance



Gate Charge

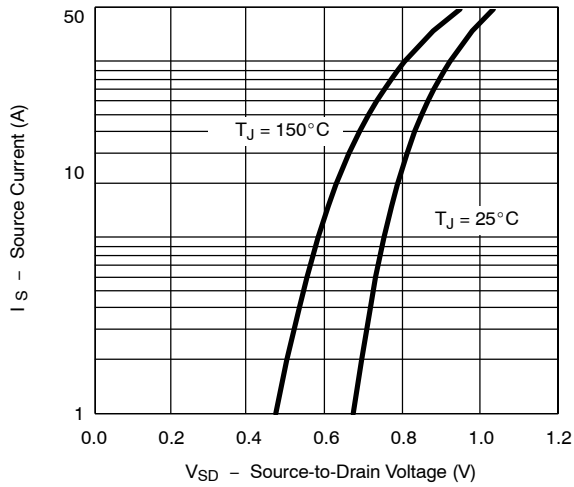


On-Resistance vs. Junction Temperature

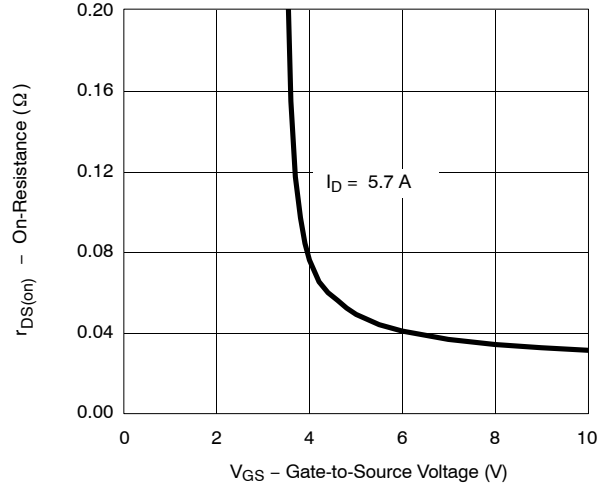


TYPICAL CHARACTERISTICS (25 °C UNLESS NOTED)

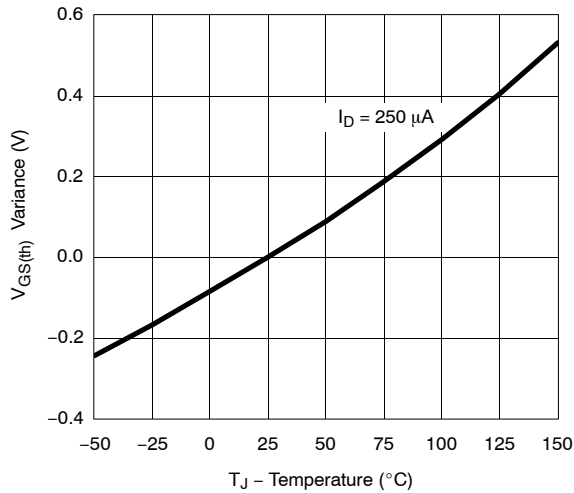
Source-Drain Diode Forward Voltage



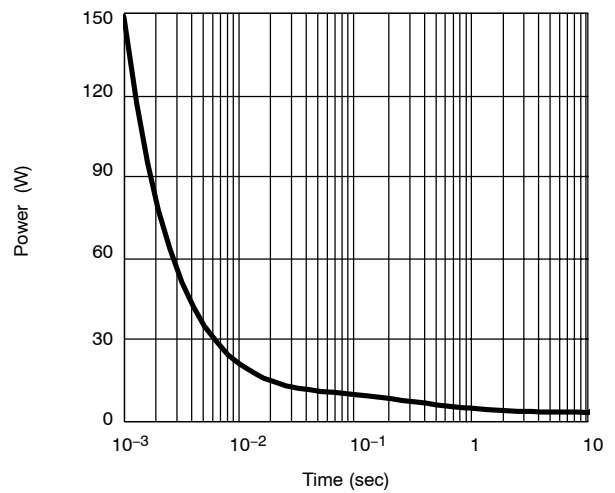
On-Resistance vs. Gate-to-Source Voltage



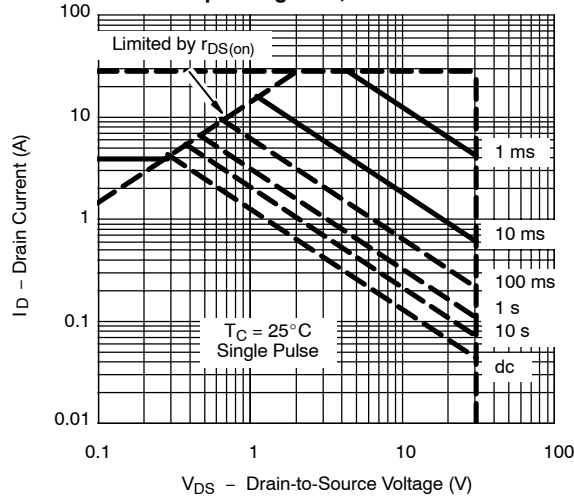
Threshold Voltage



Single Pulse Power, Junction-to-Ambient



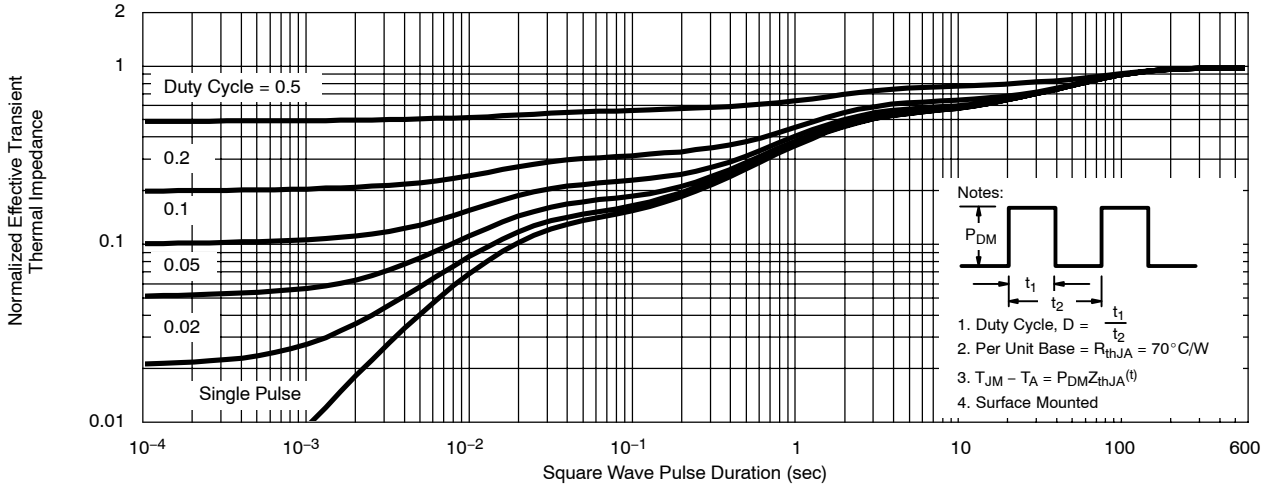
Safe Operating Area, Junction-to-Foot



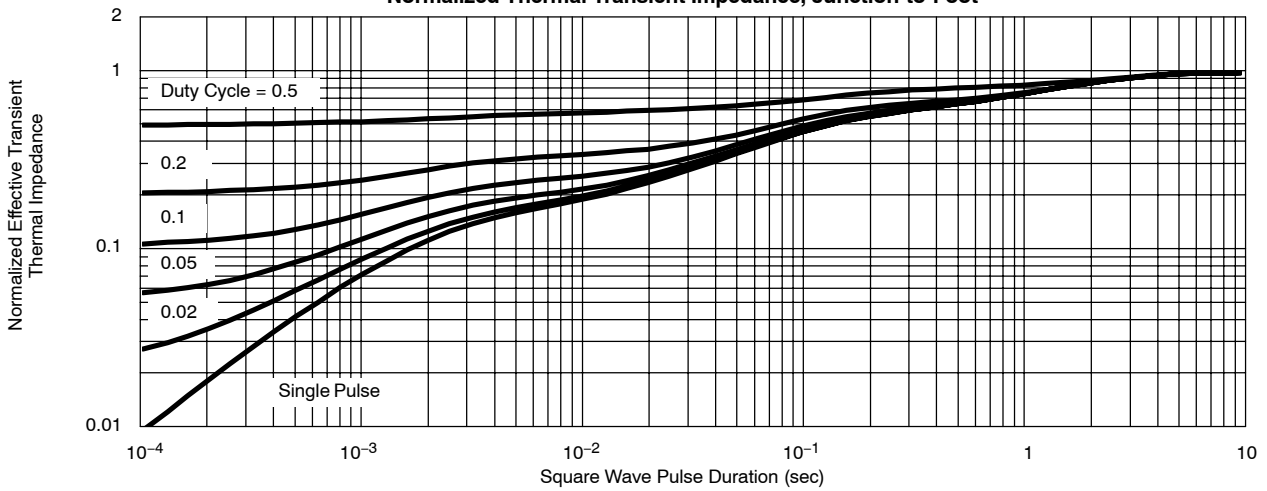


TYPICAL CHARACTERISTICS (25 °C UNLESS NOTED)

Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot





Si9435BDY vs. Si9435DY

Description: P-Channel, 30-V (D-S) MOSFET
Package: SOIC-8
Pin Out: Identical

Part Number Replacements:

- Si9435BDY Replaces Si9435DY
- Si9435BDY—E3 (Lead Free version) Replaces Si9435DY
- Si9435BDY-T1 Replaces Si9435DY-T1
- Si9435BDY-T1—E3 (Lead Free version) Replaces Si9435DY-T1

Summary of Performance:

The Si9435BDY is the replacement for the original Si9435DY; both parts perform identically including limits to the parametric tables below.

ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C UNLESS OTHERWISE NOTED)				
Parameter	Symbol	Si9435BDY	Si9435DY	Unit
Drain-Source Voltage	V _{DS}	-30	-30	V
Gate-Source Voltage	V _{GS}	± 20	± 20	
Continuous Drain Current	T _A = 25 °C	-5.7	-5.1	A
	T _A = 70 °C	-4.6	-4.6	
Pulsed Drain Current	I _{DM}	-30	-20	
Continuous Source Current (MOSFET Diode Conduction)	I _S	-2.3	-2.6	
Power Dissipation	T _A = 25 °C	2.5	2.5	W
	T _A = 70 °C	1.6	1.6	
Operating Junction and Storage Temperature Range	T _J and T _{stg}	-55 to 150	-55 to 150	°C
Maximum Junction-to-Ambient	R _{thJA}	50	50	°C/W

SPECIFICATIONS (T_J = 25 °C UNLESS OTHERWISE NOTED)								
Parameter	Symbol	Si9435BDY			Si9435DY			Unit
		Min	Typ	Max	Min	Typ	Max	
Static								
Gate-Threshold Voltage	V _{G(th)}	-1.0		-3.0	-1.0			V
Gate-Body Leakage	I _{GSS}			± 100			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}			-1			-1	µA
On-State Drain Current	V _{GS} = -10 V	-20			-20			A
	V _{GS} = -4.5 V	NS			-5			
Drain-Source On-Resistance	V _{GS} = -10 V		0.033	0.042		0.037	0.055	Ω
	V _{GS} = -6 V		0.043	0.055		0.047	0.07	
	V _{GS} = -4.5 V		0.056	0.070		0.060	0.105	
Forward Transconductance	g _{fs}		13			9		S
Diode Forward Voltage	V _{SD}		-0.8	-1.1		-0.88	-1.2	V
Dynamic								
Total Gate Charge	Q _g		16	24		27	40	nC
Gate-Source Charge	Q _{gs}		2.3			4		
Gate-Drain Charge	Q _{gd}		4.5			6.3		
Gate Resistance	R _g		8.8			NS		Ω
Switching								
Turn-On Time	t _{d(on)}		14	25		14	30	ns
	t _r		14	25		13	60	
Turn-Off Time	t _{d(off)}		42	70		58	120	
	t _f		30	50		21	100	
Source-Drain Reverse Recovery Time	t _{rr}		30	60		65	100	

NS denotes parameter not specified in original data sheet.



P-CHANNEL ACCELERATED OPERATING LIFE TEST RESULT	
Sample Size	24,025
Equivalent Device Hours	2,387,081,631
Number of Total Failures	0
Failure Rate in FIT	0.381

Failure Rate in FIT is calculated according to JEDEC Standard JESD85, *Methods for Calculating Failure Rates in Units of FITs*, based on accelerated high temperature operating life test results by using an apparent activation energy of 0.7 eV. The junction temperature of the device at use is assumed to be 55°C. A constant failure rate distribution is assumed. The upper confidence bound of the failure rate is 60%.



ENVIRONMENTAL AND PACKAGE TESTING DATA FOR SOIC 8-LEAD

Stress	Sample Size	Device Hr./Cyc	Condition	Total Fails	Fail Percentage
85/85	1,132	1,122,016	85°C, 85%RH	0	0.00
BOND INT	3,520	1,626,400	200°C + N2	0	0.00
DIE SHEAR	20	1,600	MIL-STD-750	0	0.00
HAST	27,813	2,662,790	130°C, 85%RH	0	0.00
HIGH TEMP STORAGE	656	286,320	200°C	0	0.00
Power Cycle	164	1,932,904	DELTA Tj=100	0	0.00
Pressure Pot	34,316	3,501,244	121°, 15 PSIG	0	0.00
Solder DUNK	4,662	14,442	260°C, 10SEC	0	0.00
Solderability	1,580	11,805	883 M2003	0	0.00
Temp Cycle	37,176	24,624,654	-65°C - 150°C	0	0.00
Thermal Shock	11,400	1,150,000	-60°C - 150°C	0	0.00



P-Channel 30-V (D-S) MOSFET

CHARACTERISTICS

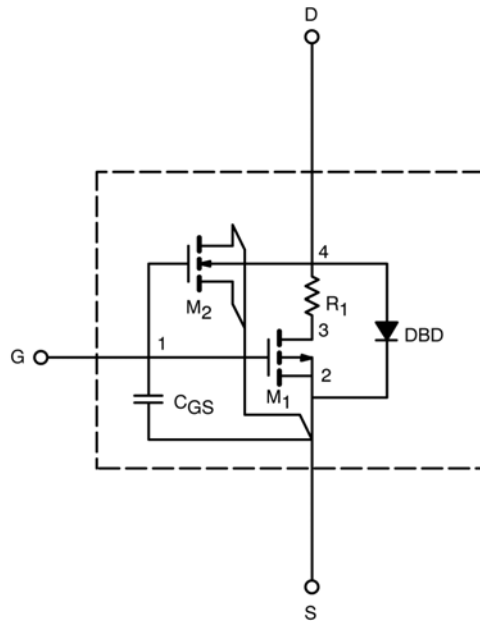
- P-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the -55 to 125°C Temperature Range
- Model the Gate Charge, Transient, and Diode Reverse Recovery Characteristics

DESCRIPTION

The attached spice model describes the typical electrical characteristics of the p-channel vertical DMOS. The subcircuit mode is extracted and optimized over the -55 to 125°C temperature ranges under the pulsed 0-to-10V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched C_{gd} model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

SUBCIRCUIT MODEL SCHEMATIC



This document is intended as a SPICE modeling guideline and does not constitute a commercial product data sheet. Designers should refer to the appropriate data sheet of the same number for guaranteed specification limits.



SPECIFICATIONS ($T_J = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)					
Parameter	Symbol	Test Conditions	Simulated Data	Measured Data	Unit
Static					
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	2.1		V
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} = -5\text{V}, V_{GS} = -10\text{V}$	133		A
Drain-Source On-State Resistance ^a	$r_{DS(on)}$	$V_{GS} = -10\text{V}, I_D = -5.7\text{A}$	0.032	0.033	Ω
		$V_{GS} = -6\text{V}, I_D = -5\text{A}$	0.041	0.043	
		$V_{GS} = -4.5\text{V}, I_D = -4.4\text{A}$	0.055	0.056	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -15\text{V}, I_D = -5.7\text{A}$	11	13	S
Diode Forward Voltage ^a	V_{SD}	$I_S = -2.3\text{A}, V_{GS} = 0\text{V}$	-0.82	-0.80	V
Dynamic^b					
Total Gate Charge	Q_g	$V_{DS} = -15\text{V}, V_{GS} = -10\text{V}, I_D = -3.5\text{A}$	13	16	nC
Gate-Source Charge	Q_{gs}		2.3	2.3	
Gate-Drain Charge	Q_{gd}		4.5	4.5	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -15\text{V}, R_L = 15\Omega$ $I_D \cong -1\text{A}, V_{GEN} = -10\text{V}, R_G = 6\Omega$	31	30	ns
Rise Time	t_r		19	14	
Turn-Off Delay Time	$t_{d(off)}$		72	42	
Fall Time	t_f		16	30	

Notes

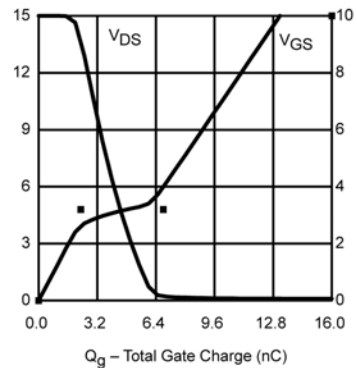
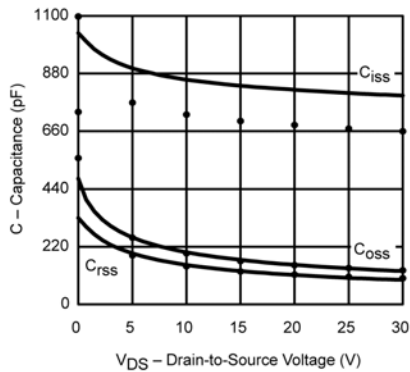
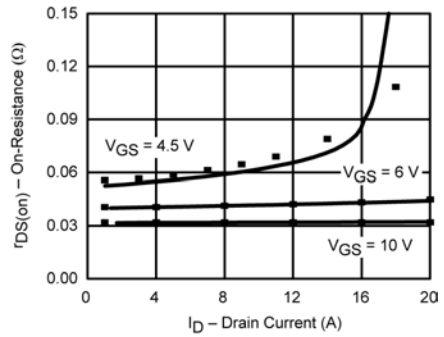
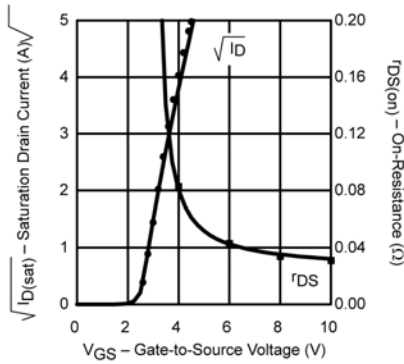
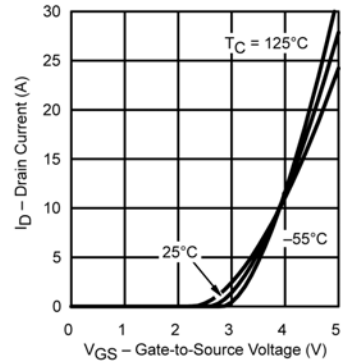
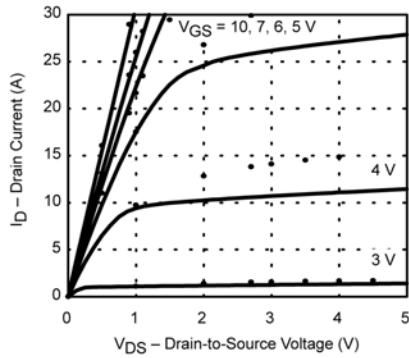
- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
- b. Guaranteed by design, not subject to production testing.



SPICE Device Model Si9435BDY

Vishay Siliconix

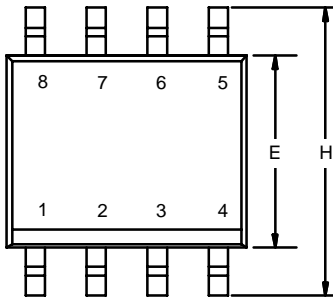
COMPARISON OF MODEL WITH MEASURED DATA ($T_J=25^\circ\text{C}$ UNLESS OTHERWISE NOTED)



Note: Dots and squares represent measured data.

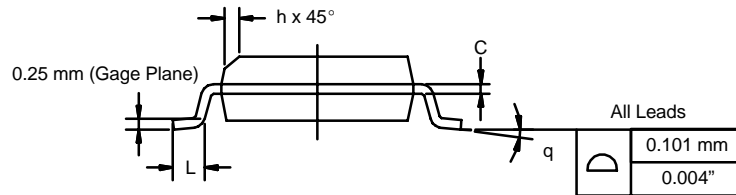
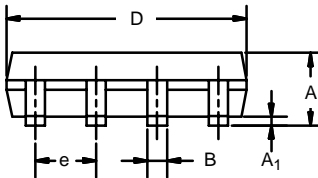


SOIC (NARROW): 8-LEAD
JEDEC Part Number: MS-012



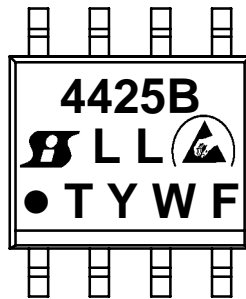
Dim	MILLIMETERS		INCHES	
	Min	Max	Min	Max
A	1.35	1.75	0.053	0.069
A₁	0.10	0.20	0.004	0.008
B	0.35	0.51	0.014	0.020
C	0.19	0.25	0.0075	0.010
D	4.80	5.00	0.189	0.196
E	3.80	4.00	0.150	0.157
e	1.27 BSC		0.050 BSC	
H	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.020
L	0.50	0.93	0.020	0.037
q	0°	8°	0°	8°

ECN: T-04451—Rev. H, 30-Aug-04
DWG: 5498



DEVICE: SO-8

SO-8 Devices



4425 = Example Base Part Number 1

B = Revision if applicable, where part number format is Si4425BDY for example.

 **= Siliconix Logo**

LL = Lot Code

 **= ESD Symbol**

● = Pin 1 Indicator

T = Assembly Factory Code

Y = Year Code

W = Week Code

F = Wafer Fab Code

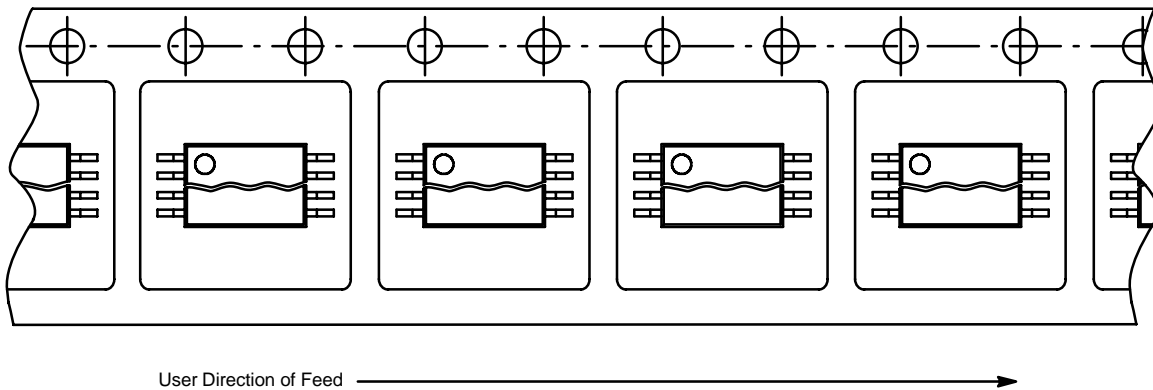
NOTE:

1. For analog switches base part includes DG prefix. Package suffix may or may not be present, depending on room available.

The current marking strategy is reflected. Contact your local sales representative for historical marking strategies for these packages.

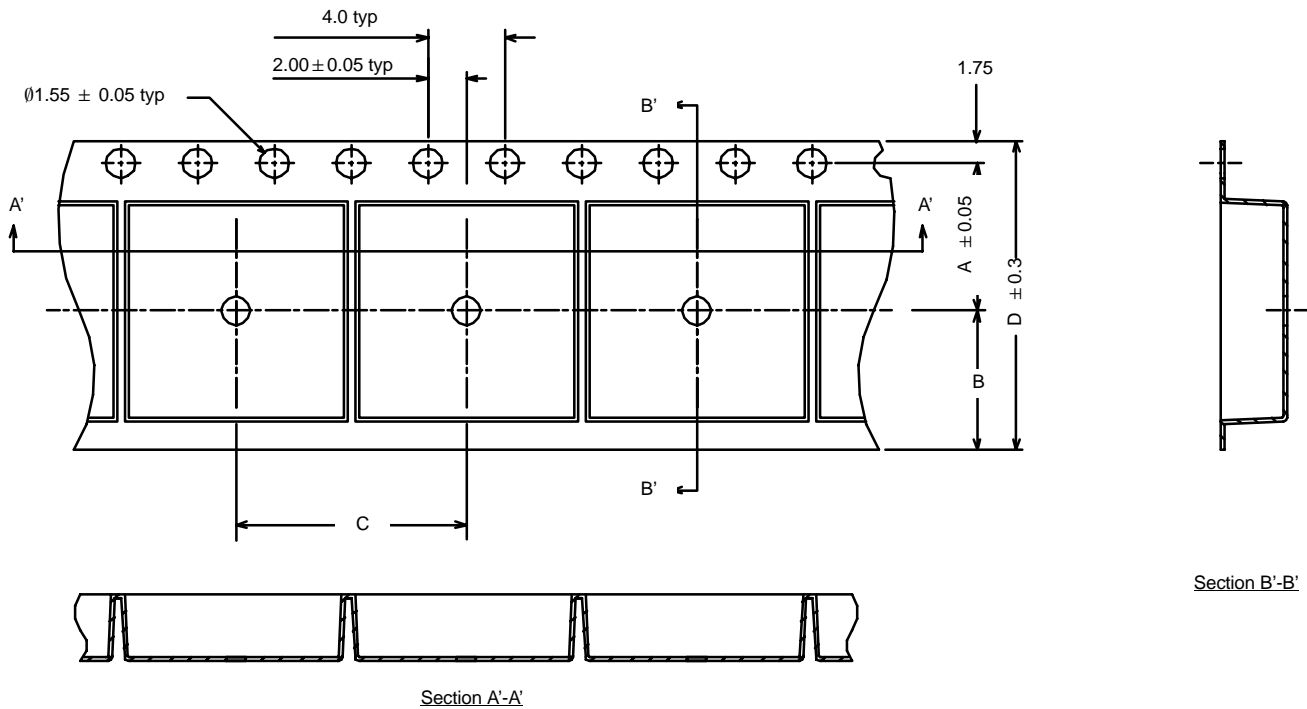
Device Orientation MSOP, SOIC, SSOP and TSSOP Devices

DEVICE ORIENTATION	
Package	Method
MSOP	T1
SOIC	T1
SSOP	T1
TSSOP	T1



Revision control of this drawing is maintained through Document Control, Pack Specification—PACK-0007-6.
ECN: S-41078, Rev. BK, 28-Jun-04

SOIC PACKAGES (NARROW AND WIDE BODY)



NOTES:

1. Material: Black conductive or Black static dissipative.
2. All dimensions in millimeters unless otherwise specified.
3. Tolerances unless specified will be ± 0.10 mm.

PACKAGE	A	B	C	D	REEL DIAMETER	QUANTITY PER REEL
SOIC-16(N)	7.5	6.75	8	16	330	2,500
SOIC-14(N)	7.5	6.75	8	16	330	2,500
SOIC-8(N)	5.5	4.75	8	12	330 min	2,500
SOIC-14(W)	7.5	6.75	12	16	330	1,500
SOIC-16(W)	7.5	6.75	12	16	330	1,500(T1)
SOIC-24(W)	11.5	10.75	12	24	330	1,500
SOIC-20(W)	11.5	10.75	12	24	330	1,500
SOIC-8(N) Simconix	5.5	4.75	8	12	330 min	2,500

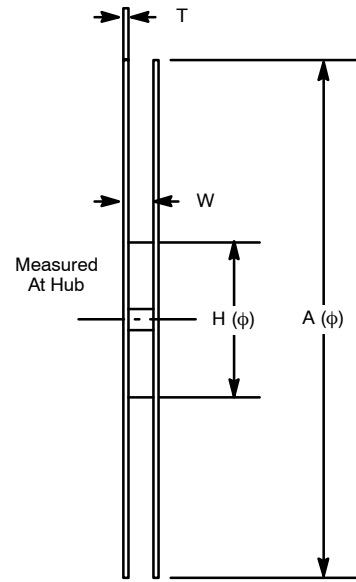
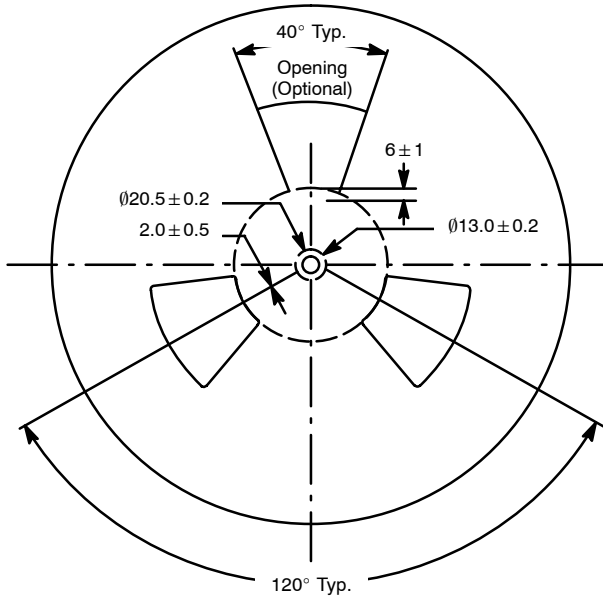
ECN: S-40347—Rev. AA, 29-Mar-04
DWG: 91-5209-x



LOK REEL

Reel Information

Vishay Siliconix



NOTES:

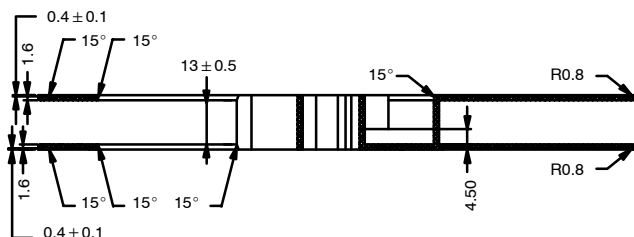
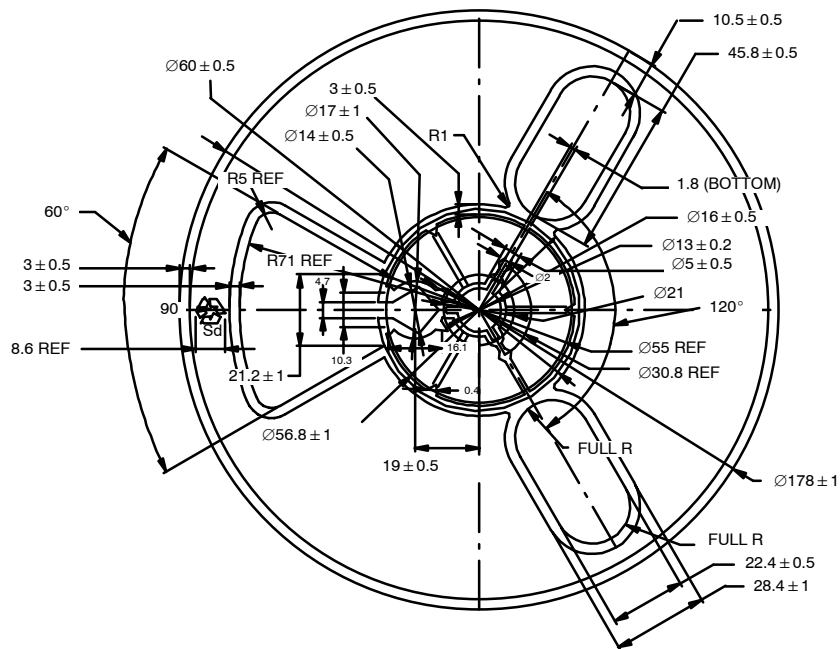
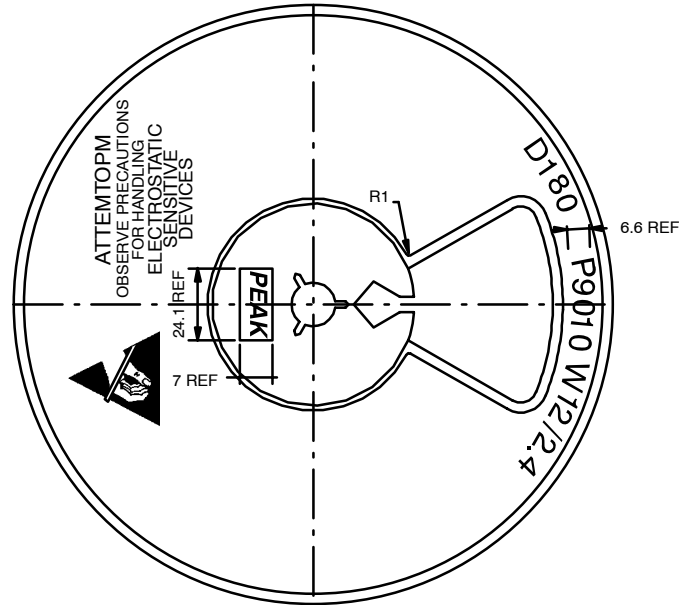
1. Material: Antistatic Plastic (High Impact Polystyrene)
2. Shelf Life: 2 years
3. Color: White (Blue for special)

VER	APPLICATION	A	W	TAPE WIDTH	H	T
-1	SOIC-14/16 TO-251 (Short Lead) TO-252/TO-252 (Reverse Lead) PLCC-20 TSSOP-8/16/20/28 SSOP-24 SOIC-16 (W)	330 ± 2	16.4 ^{+2.0} ₋₀	16	100 ± 1	2.5 ± 0.5
-2	SOIC-8 MSOP-8/10 PowerPAK® SO-8 PowerPAK 1212 MICRO FOOT® MLP33-5 QFN (4x4)/(3x3)	330 ± 2	12.4 ^{+2.0} ₋₀	12	100 ± 2	2.5 ± 0.5
-3	SOT-23/143 TSOP-5/6 1206-8 ChipFET® SC70/SC75A/SC89 MICRO FOOT MLP33-10 PowerPAK MLP33-8 SC-89 (SOT-666) SOT23-5, 6	178 ± 2	8.4 ^{+1.5} ₋₀	8.4	62 ± 2 or 55 ± 2	2 ± 1
-4	SOT-23/143 SC70 MICRO FOOT	330 ± 2	8.4 ^{+1.5} ₋₀	8.4	100 ± 1	2.5 ± 0.5
-5	SOIC-20(W)/24(W) D ² PAK SSOP-28 QSOP-36	330 ± 2	24.4 ^{+2.0} ₋₀	24	100 ± 1	2.5 ± 0.5
-6	TO-220 (for Kimball, V30114-T1)	330 ± 2	32 ^{+2.0} ₋₀	32	100 ± 1	2.5 ± 0.5
-7	MICRO FOOT PowerPAK 2x5	178 ± 2	12.4 ^{+2.0} ₋₀	12	55 ± 2	1.6 ± 0.25

NOTE: 93-5211-7, see page 2 for drawing detail.

ECN: S-41044—Rev. AH, 19-Jul-04
DWG: 93-5211-x

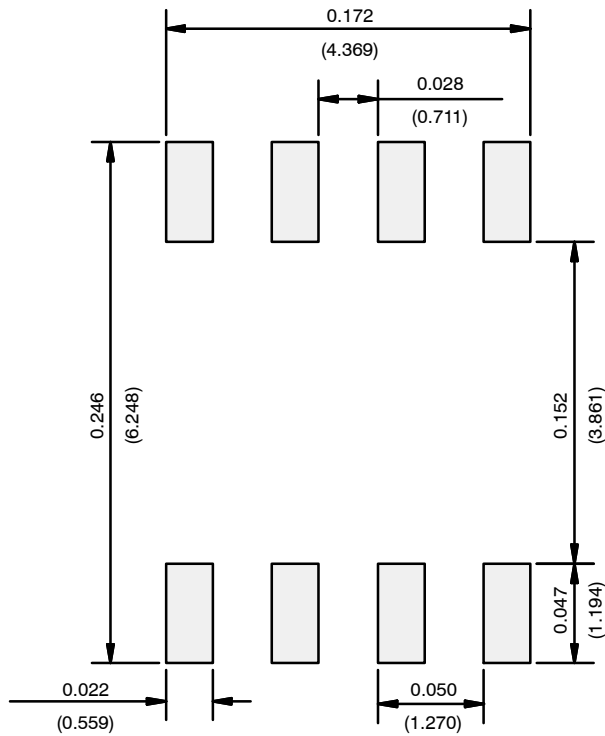
LOK REEL (DRAWING DETAIL)



NOTES:

1. Material: Polystyrene (white)
2. Antistatic Coated
3. Flange Warpage: 3 mm max.
4. All Dimensions in mm
5. ESD—Surface Resistivity $10^8 \sim 10^{11} \Omega/\text{sq}$.
6. General Tolerance: $\pm 0.25 \text{ mm}$
7. Part Number: P9010

RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads
Dimensions in Inches/(mm)

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Mounting LITTLE FOOT[®] SO-8 Power MOSFETs

Wharton McDaniel

Surface-mounted LITTLE FOOT power MOSFETs use integrated circuit and small-signal packages which have been modified to provide the heat transfer capabilities required by power devices. Leadframe materials and design, molding compounds, and die attach materials have been changed, while the footprint of the packages remains the same.

See Application Note 826, *Recommended Minimum Pad Patterns With Outline Drawing Access for Vishay Siliconix MOSFETs*, (<http://www.vishay.com/doc?72286>), for the basis of the pad design for a LITTLE FOOT SO-8 power MOSFET. In converting this recommended minimum pad to the pad set for a power MOSFET, designers must make two connections: an electrical connection and a thermal connection, to draw heat away from the package.

In the case of the SO-8 package, the thermal connections are very simple. Pins 5, 6, 7, and 8 are the drain of the MOSFET for a single MOSFET package and are connected together. In a dual package, pins 5 and 6 are one drain, and pins 7 and 8 are the other drain. For a small-signal device or integrated circuit, typical connections would be made with traces that are 0.020 inches wide. Since the drain pins serve the additional function of providing the thermal connection to the package, this level of connection is inadequate. The total cross section of the copper may be adequate to carry the current required for the application, but it presents a large thermal impedance. Also, heat spreads in a circular fashion from the heat source. In this case the drain pins are the heat sources when looking at heat spread on the PC board.

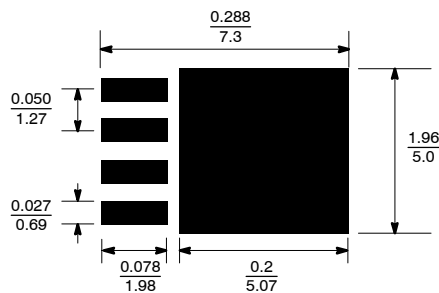


FIGURE 1. Single MOSFET SO-8 Pad Pattern With Copper Spreading

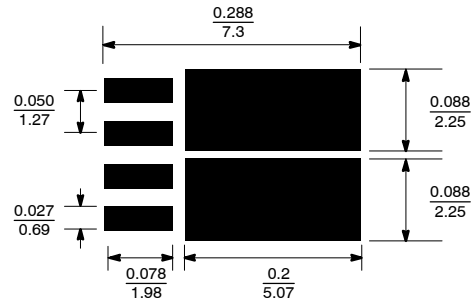


FIGURE 2. Dual MOSFET SO-8 Pad Pattern With Copper Spreading

The minimum recommended pad patterns for the single-MOSFET SO-8 with copper spreading (Figure 1) and dual-MOSFET SO-8 with copper spreading (Figure 2) show the starting point for utilizing the board area available for the heat-spreading copper. To create this pattern, a plane of copper overlies the drain pins. The copper plane connects the drain pins electrically, but more importantly provides planar copper to draw heat from the drain leads and start the process of spreading the heat so it can be dissipated into the ambient air. These patterns use all the available area underneath the body for this purpose.

Since surface-mounted packages are small, and reflow soldering is the most common way in which these are affixed to the PC board, "thermal" connections from the planar copper to the pads have not been used. Even if additional planar copper area is used, there should be no problems in the soldering process. The actual solder connections are defined by the solder mask openings. By combining the basic footprint with the copper plane on the drain pins, the solder mask generation occurs automatically.

A final item to keep in mind is the width of the power traces. The absolute minimum power trace width must be determined by the amount of current it has to carry. For thermal reasons, this minimum width should be at least 0.020 inches. The use of wide traces connected to the drain plane provides a low impedance path for heat to move away from the device.